

REMARKS

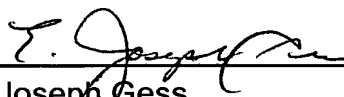
Entry of the foregoing and consideration of the subject matter identified in caption are respectfully requested. The above amendments have been made to the specification to insert appropriate headings, and Claims 4, 6 and 8-13 have been amended to remove the multiple dependencies. New Claims 14-33 have accordingly been added and correspond to the subject matter of the original claims.

If there are any questions concerning this paper or the application in general, the Examiner is invited to telephone the undersigned at his or her earliest convenience.

A favorable consideration on the merits is believed to be next in order, and is earnestly solicited.

Respectfully submitted,

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Date: August 6, 2001

Attachment to PRELIMINARY AMENDMENT dated August 6, 2001

Marked-up Claims 4, 6 and 8-13

Please amend Claims 4, 6 and 8-13 as follows:

4. (Amended) Control method according to Claim 1 [one of Claims 1 to 3], characterized in that the ellipsometric measurement is one with phase modulation.

6. (Amended) Control method according to Claim 1 [one of Claims 1 to 3], characterized in that the ellipsometric measurement is carried out using the method called "rotating polarizer" method.

8. (Amended) Control method according to Claim 1 [any one of Claims 1 to 7], characterized in that the ellipsometric measurement is a multiwavelength measurement.

9. (Amended) Control method according to Claim 1 [any one of Claims 1 to 8], characterized in that the reference values form a theoretically determined path.

10. (Amended) Control method according to Claim 1 [any one of Claims 1 to 8], characterized in that the reference values form an experimentally determined path.

Attachment to PRELIMINARY AMENDMENT dated August 6, 2001

Marked-up Claims 4, 6 and 8-13

11. (Amended) Control method according to Claim 1 [any one of Claims 1 to 10], characterized in that the reference values are discrete points corresponding to the instants of fabrication of the thin layers with respect to the time t_0 .

12. (Amended) Control method according to Claim 1 [any one of Claims 1 to 11], characterized in that the path traveled is adjusted by a polynomial of order between 1 and 5.

13. (Amended) Control method according to Claim 1 [any one of Claims 1 to 12], characterized in that the reference values are determined by measurement, using the succession of the following steps:

- measurement of a known layer on a simple substrate;
- measurement of the same known layer on an industrial substrate;
- measurement of the thin-film structure [structre] to be controlled.